

OptiMOS® Buck converter series

Feature

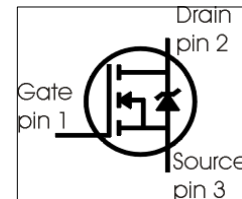
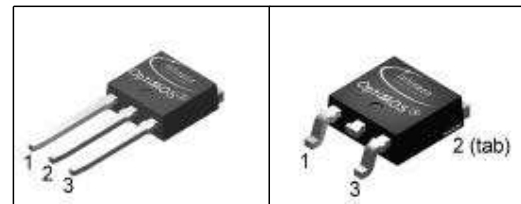
- N-Channel
- Logic Level
- Low On-Resistance $R_{DS(on)}$
- Excellent Gate Charge x $R_{DS(on)}$ product (FOM)
- Superior thermal resistance
- 175°C operating temperature
- Avalanche rated
- dv/dt rated
- Ideal for fast switching buck converters

Product Summary

| | | |
|--------------|-----|----|
| V_{DS} | 30 | V |
| $R_{DS(on)}$ | 6.8 | mΩ |
| I_D | 30 | A |

P- TO251 -3-1

P- TO252 -3-11



| Type | Package | Ordering Code | Marking |
|-----------|----------------|---------------|---------|
| IPD07N03L | P- TO252 -3-11 | Q67042-S4029 | 07N03L |
| IPU07N03L | P- TO251 -3-1 | Q67042-S4105 | 07N03L |

Maximum Ratings, at $T_j = 25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|---|---------------------|-------------|-------------------|
| Continuous drain current ¹⁾ $T_C=25\text{ °C}$ | I_D | 30 30 | A |
| Pulsed drain current $T_C=25\text{ °C}$ | $I_{D\text{ puls}}$ | 120 | |
| Avalanche energy, single pulse $I_D=20\text{ A}$, $V_{DD}=25\text{ V}$, $R_{GS}=25\text{ }\Omega$ | E_{AS} | 30 | mJ |
| Repetitive avalanche energy, limited by $T_{jmax}^{2)}$ | E_{AR} | 15 | |
| Reverse diode dv/dt $I_S=30\text{ A}$, $V_{DS}=24\text{ V}$, $di/dt=200\text{ A}/\mu\text{s}$, $T_{jmax}=175\text{ °C}$ | dv/dt | 6 | kV/ μs |
| Gate source voltage | V_{GS} | ± 20 | V |
| Power dissipation $T_C=25\text{ °C}$ | P_{tot} | 150 | W |
| Operating and storage temperature | T_j, T_{stg} | -55... +175 | °C |
| IEC climatic category; DIN IEC 68-1 | | 55/175/56 | |

Thermal Characteristics

| Parameter | Symbol | Values | | | Unit |
|---|------------|--------|------|----------|------|
| | | min. | typ. | max. | |
| Characteristics | | | | | |
| Thermal resistance, junction - case | R_{thJC} | - | 0.68 | 1 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | - | - | 100 | |
| SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ³⁾ | R_{thJA} | - | - | 75 50 | |

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|--|---------------|--------|------------|----------|------------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$ | $V_{(BR)DSS}$ | 30 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 80 \mu A$ | $V_{GS(th)}$ | 1.2 | 1.6 | 2 | |
| Zero gate voltage drain current $V_{DS}=30V, V_{GS}=0V, T_j=25^\circ\text{C}$ $V_{DS}=30V, V_{GS}=0V, T_j=125^\circ\text{C}$ | I_{DSS} | - | 0.01 10 | 1 100 | μA |
| Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$ | I_{GSS} | - | 1 | 100 | |
| Drain-source on-state resistance $V_{GS}=4.5V, I_D=30A$ | $R_{DS(on)}$ | - | 7.7 | 9.9 | m Ω |
| Drain-source on-state resistance $V_{GS}=10V, I_D=30A$ | $R_{DS(on)}$ | - | 5.7 | 6.8 | |

¹Current limited by bondwire ; with an $R_{thJC} = 1K/W$ the chip is able to carry $I_D = 116A$ at 25°C , for detailed information see app.-note ANPS071E available at www.infineon.com/optimos

²Defined by design. Not subject to production test.

³Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic Characteristics

| | | | | | | |
|------------------------------|--------------|---|----|------|------|----------|
| Transconductance | g_{fs} | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$, $I_D = 30A$ | 29 | 58 | - | S |
| Input capacitance | C_{iss} | $V_{GS} = 0V$, $V_{DS} = 25V$, $f = 1MHz$ | - | 1900 | 2530 | pF |
| Output capacitance | C_{oss} | | - | 740 | 990 | |
| Reverse transfer capacitance | C_{rss} | | - | 180 | 270 | |
| Gate resistance | R_G | | - | 2.3 | - | Ω |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = 15V$, $V_{GS} = 10V$, $I_D = 15A$, $R_G = 3.6\Omega$ | - | 7.8 | 11.7 | ns |
| Rise time | t_r | | - | 17 | 26 | |
| Turn-off delay time | $t_{d(off)}$ | | - | 62 | 93 | |
| Fall time | t_f | | - | 47 | 70 | |

Gate Charge Characteristics

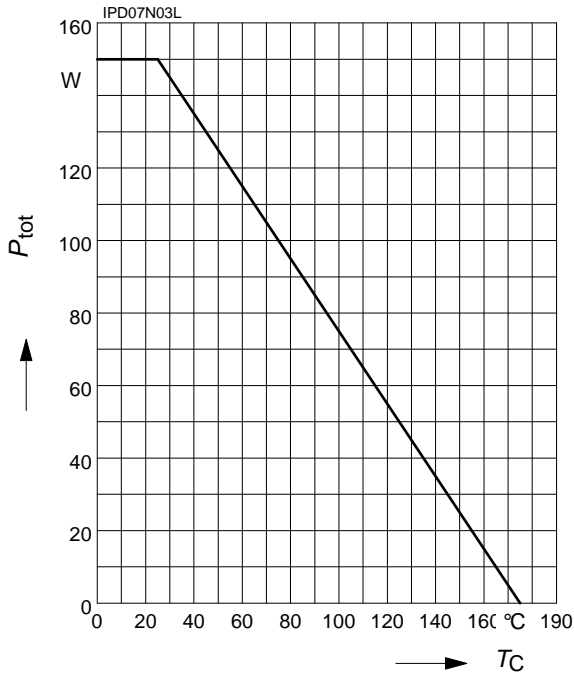
| | | | | | | |
|-----------------------|-----------------|--|---|------|------|----|
| Gate to source charge | Q_{gs} | $V_{DD} = 15V$, $I_D = 15A$ | - | 4.4 | 5.5 | nC |
| Gate to drain charge | Q_{gd} | | - | 14.8 | 18.1 | |
| Gate charge total | Q_g | $V_{DD} = 15V$, $I_D = 15A$, $V_{GS} = 0$ to 5V | - | 26.8 | 33.5 | |
| Output charge | Q_{oss} | $V_{DS} = 15V$, $I_D = 15A$, $V_{GS} = 0V$ | - | 25.5 | 31.9 | nC |
| Gate plateau voltage | $V_{(plateau)}$ | $V_{DD} = 15V$, $I_D = 15A$ | - | 2.5 | - | V |

Reverse Diode

| | | | | | | |
|--|----------|-----------------------------|---|-----|-----|----|
| Inverse diode continuous forward current | I_S | $T_C = 25^\circ C$ | - | - | 30 | A |
| Inv. diode direct current, pulsed | I_{SM} | | - | - | 120 | |
| Inverse diode forward voltage | V_{SD} | $V_{GS} = 0V$, $I_F = 30A$ | - | 0.9 | 1.3 | V |
| Reverse recovery time | t_{rr} | $V_R = 15V$, $I_F = I_S$, | - | 41 | 51 | ns |
| Reverse recovery charge | Q_{rr} | $di/dt = 100A/\mu s$ | - | 46 | 58 | nC |

1 Power dissipation

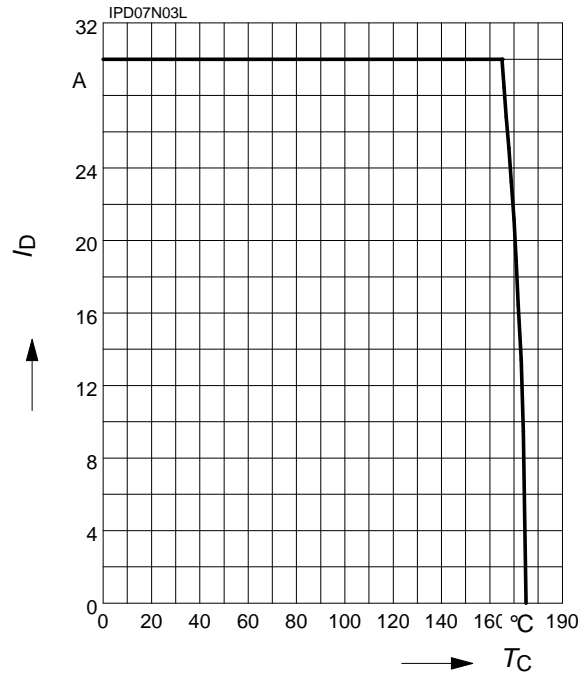
$P_{tot} = f(T_C)$



2 Drain current

$I_D = f(T_C)$

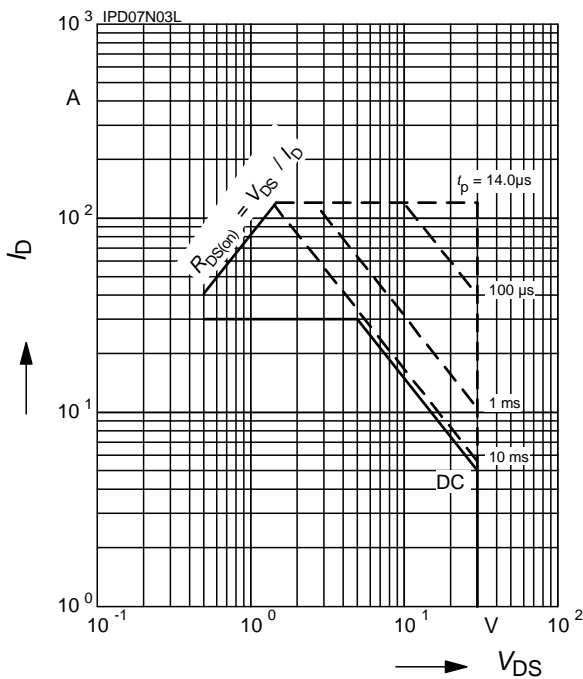
parameter: $V_{GS} \geq 10\text{ V}$



3 Safe operating area

$I_D = f(V_{DS})$

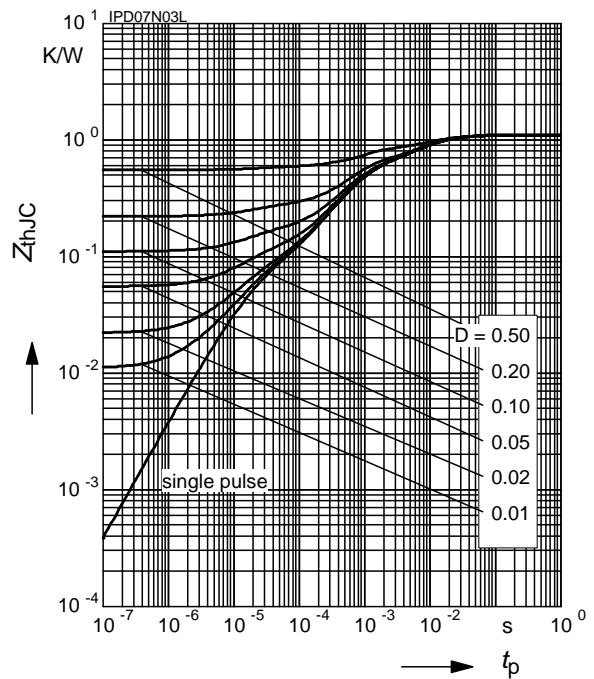
parameter: $D = 0$, $T_C = 25\text{ °C}$



4 Max. transient thermal impedance

$Z_{thJC} = f(t_p)$

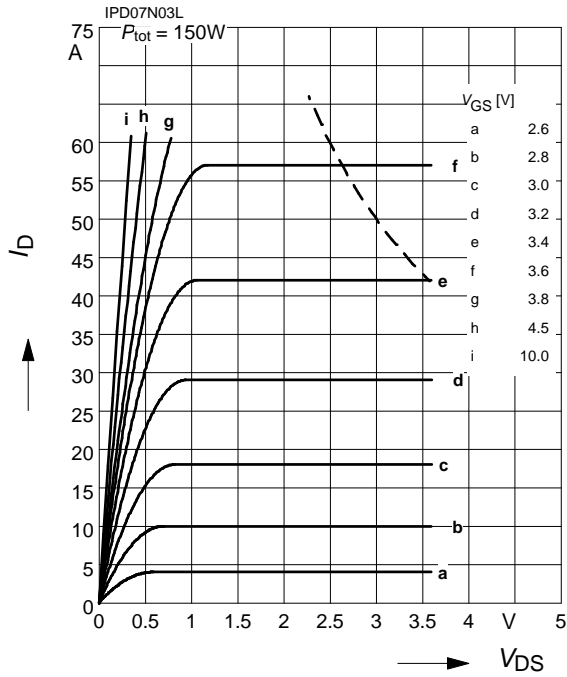
parameter: $D = t_p/T$



5 Typ. output characteristic

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$

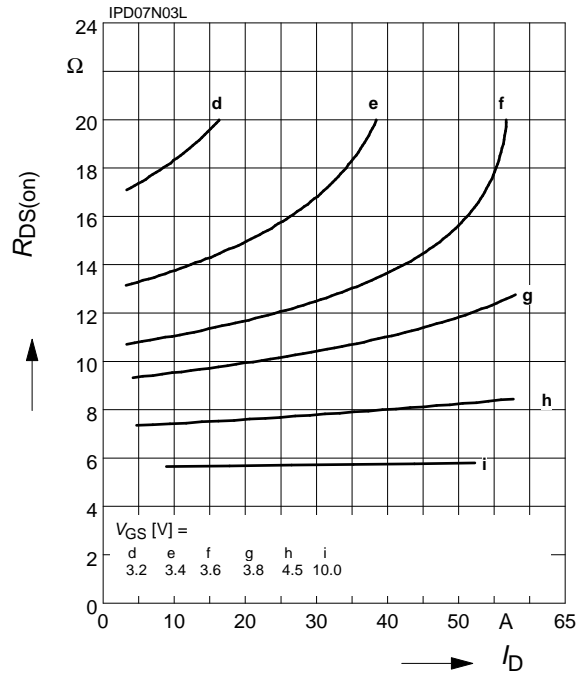
parameter: $t_p = 80 \mu\text{s}$



6 Typ. drain-source on resistance

$R_{DS(on)} = f(I_D)$

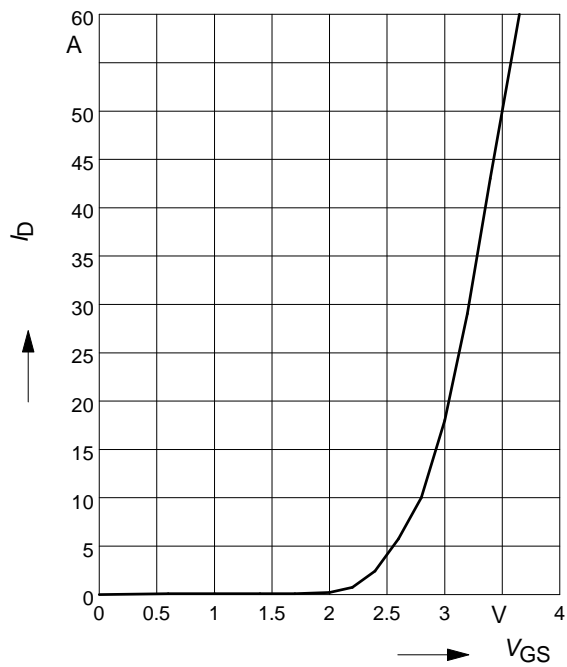
parameter: V_{GS}



7 Typ. transfer characteristics

$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

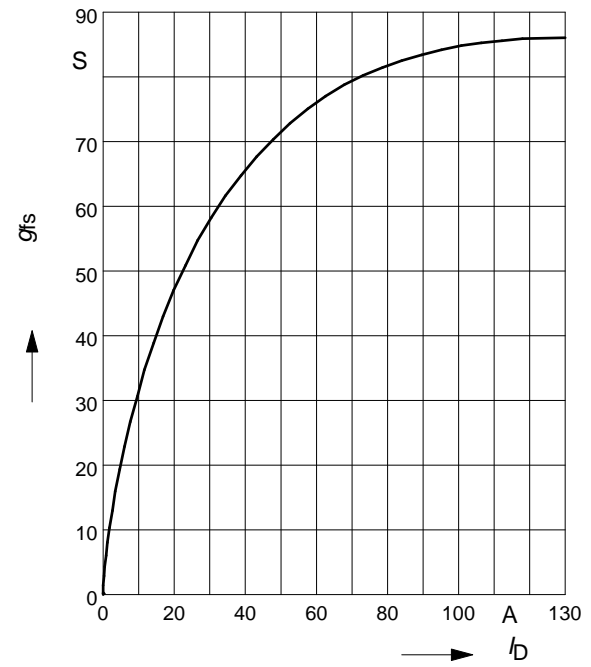
parameter: $t_p = 80 \mu\text{s}$



8 Typ. forward transconductance

$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$

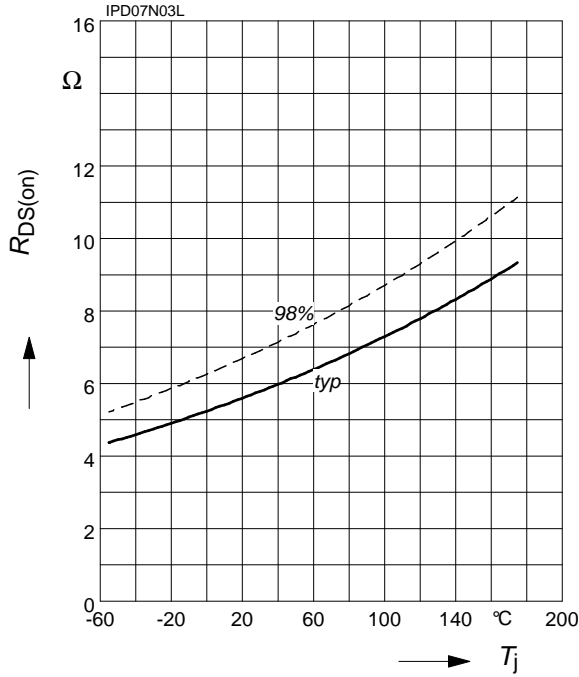
parameter: g_{fs}



9 Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

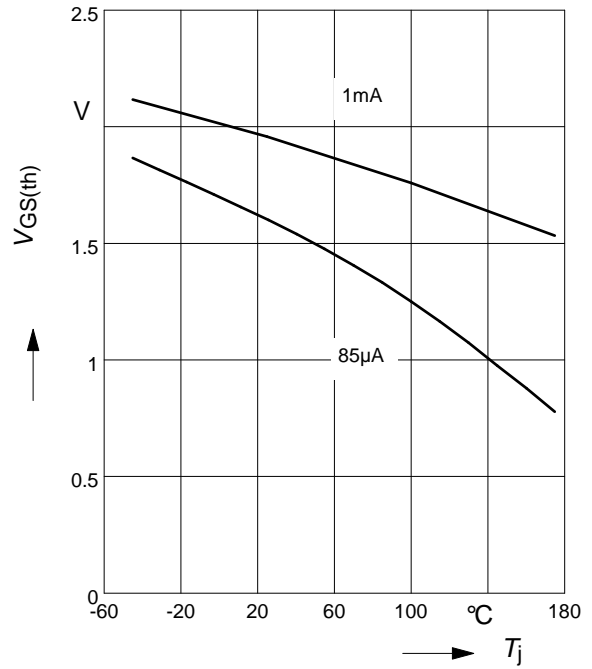
parameter: $I_D = 30\text{ A}$, $V_{GS} = 10\text{ V}$



10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

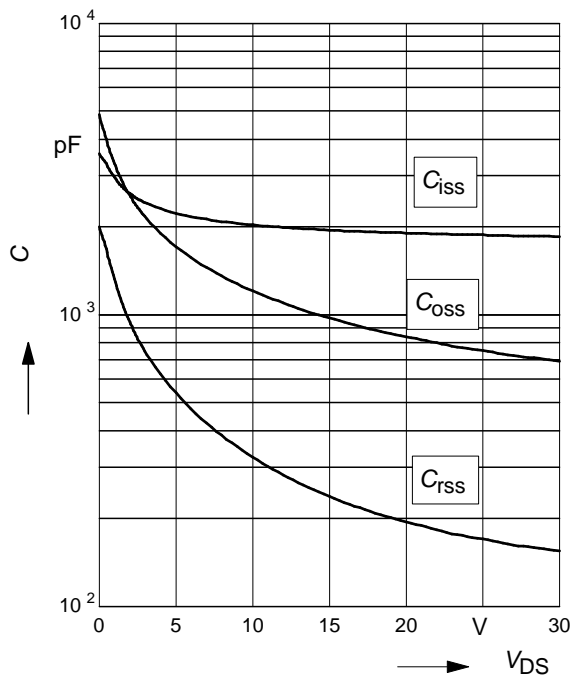
parameter: $V_{GS} = V_{DS}$



11 Typ. capacitances

$$C = f(V_{DS})$$

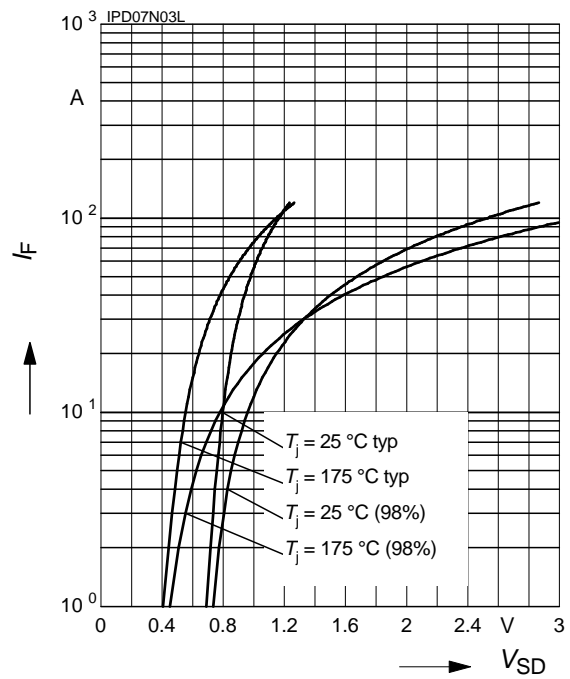
parameter: $V_{GS}=0\text{V}$, $f=1\text{ MHz}$



12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

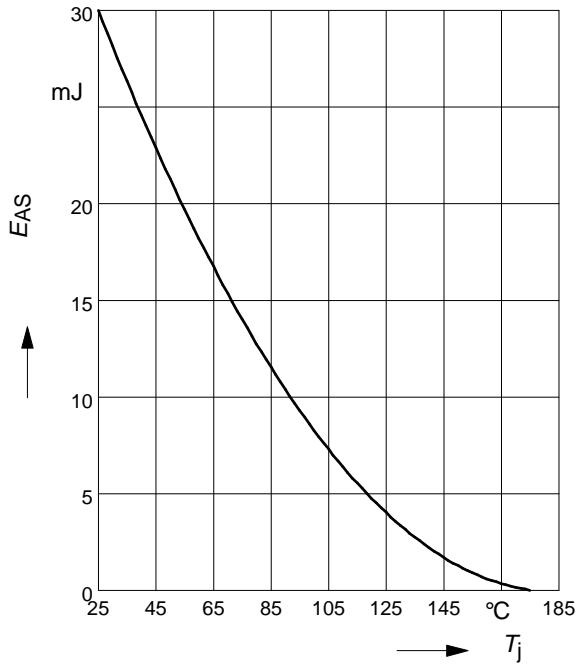
parameter: T_j , $t_p = 80\text{ }\mu\text{s}$



13 Typ. avalanche energy

$$E_{AS} = f(T_j)$$

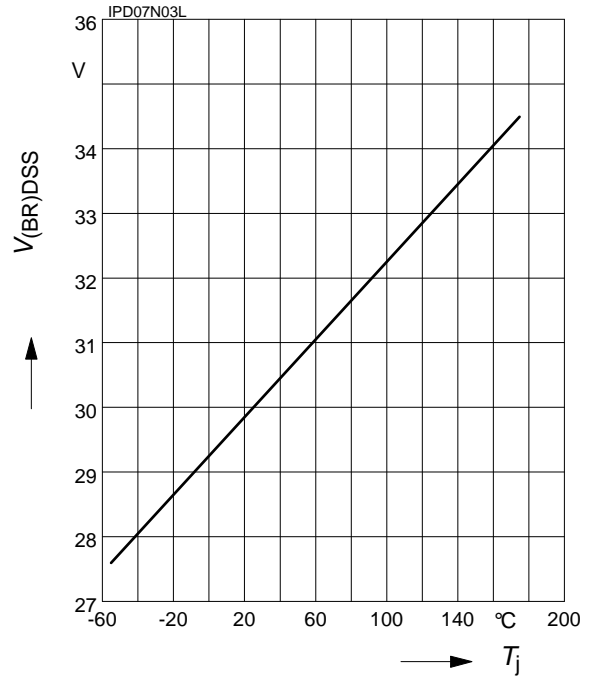
par.: $I_D = 20\text{ A}$, $V_{DD} = 25\text{ V}$, $R_{GS} = 25\ \Omega$



15 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$

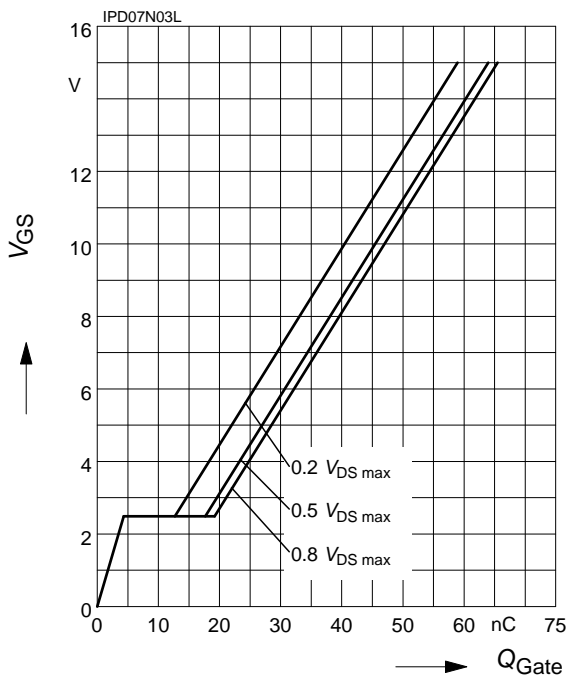
parameter: $I_D = 10\text{ mA}$



14 Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

parameter: $I_D = 15\text{ A pulsed}$





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